

# STW9NK95Z

# N-channel 950 V - 1.15 $\Omega$ - 7 A - TO-247 Zener-protected SuperMESH<sup>TM</sup> Power MOSFET

### Features

Туре	200		ID	Pw	
STW9NK95Z	950 V	< 1.38 Ω	7 A	160 W	

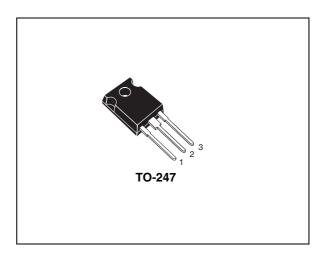
- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized

## Application

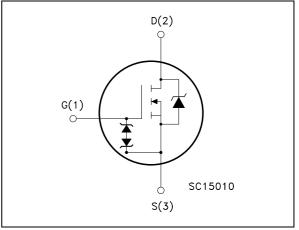
Switching applications

## Description

The SuperMESH<sup>™</sup> series is obtained through an extreme optimization of ST's well established strip-based PowerMESH<sup>™</sup> layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications.



### Figure 1. Internal schematic diagram



#### Table 1.Device summary

Order code	Marking	Package	Packaging
STW9NK95Z	9NK95Z	TO-247	Tube

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# 1 Electrical ratings

Table 2.	Absolute maximum ratings
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Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage ( $V_{GS} = 0$ )	950	V
V <sub>GS</sub>	Gate-source voltage	± 30	V
I <sub>D</sub>	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	7	А
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> =100 °C	4.41	А
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	28	А
P <sub>TOT</sub>	Total dissipation at $T_C = 25 \ ^{\circ}C$	160	W
	Derating Factor	1.28	W/°C
Vesd(G-S)	G-S ESD (HBM C=100 pF, R=1.5 kΩ)	4000	V
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	4.5	V/ns
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 150	°C

1. Pulse width limited by safe operating area

2. I\_{SD}~\leq 7 A, di/dt  $\leq$  100 A/µs,V\_{DD}~\leq 80% V  $_{(BR)DSS}$ 

### Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.78	°C/W
R <sub>thj-a</sub>	Thermal resistance junction-ambient max	50	°C/W
Τ <sub>Ι</sub>	Maximum lead temperature for soldering purpose	300	°C

#### Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AS</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_J$ Max)	7	A
E <sub>AS</sub>	Single pulse avalanche energy (starting T <sub>J</sub> =25 °C, I <sub>D</sub> =I <sub>AS</sub> , V <sub>DD</sub> =50 V) (see Figure 17)and (see Figure 18)	300	mJ

# 2 Electrical characteristics

(T<sub>CASE</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	950			V
I <sub>DSS</sub>	Zero gate voltage drain current ( $V_{GS} = 0$ )	V <sub>DS</sub> = max rating, V <sub>DS</sub> = max rating @125 °C			1 50	μA μA
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$			±10	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS}$ = $V_{GS}$ , $I_D$ = 100 $\mu$ A	3	3.75	4.5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3.6 A		1.15	1.38	Ω

#### Table 5. On/off states

### Table 6. Dynamic

	,					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 3.6 \text{ A}$		5.7		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> = 25 V, f=1 MHz, V <sub>GS</sub> = 0		2256 189 30		pF pF pF
C <sub>oss eq</sub> <sup>(2)</sup> .	Equivalent output capacitance	$V_{GS}$ =0, $V_{DS}$ =0 to 760 V		37		pF
R <sub>G</sub>	Intrinsic gate resistance	f=1 MHz, open drain		1.6		Ω
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 760 \text{ V}, I_D = 7.2 \text{ A}$ $V_{GS} = 10 \text{ V}$ <i>(see Figure 15)</i>		56 10 30		nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%

2.  $C_{oss\;eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 



	ownering three					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on delay time Rise Time	$V_{DD}$ = 475 V, I <sub>D</sub> = 3.6 A, R <sub>G</sub> = 4.7 $\Omega$ , V <sub>GS</sub> = 10 V (see Figure 14) (see Figure 19)		22 15		ns ns
t <sub>d(off)</sub> t <sub>f</sub>	Turn-off delay time Fall time	$V_{DD}$ = 475 V, I <sub>D</sub> = 3.6 A, R <sub>G</sub> = 4.7 $\Omega$ , V <sub>GS</sub> = 10 V (see Figure 14) (see Figure 19)		51 22		ns ns

 Table 7.
 Switching times

#### Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$\mathrm{BV}_{\mathrm{GSO}}^{(1)}$	Gate-source breakdown voltage	Igs=±1 mA(open drain)	30			V

 The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current				7	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)				28	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 7.2 A, V <sub>GS</sub> =0			1.6	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 7.2 A, di/dt = 100 A/μs, V <sub>DD</sub> = 60V, Tj = 25°C <i>(see Figure 16)</i>		660 5.9 18		ns μC Α
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 7.2 A, di/dt = 100 A/μs, V <sub>DD</sub> = 60V, Tj = 150°C <i>(see Figure 16)</i>		800 7.4 18.6		ns μC Α

#### Table 9. Source drain diode

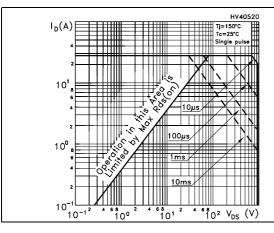
1. Pulse width limited by safe operating area

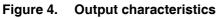
2. Pulsed: pulse duration=300µs, duty cycle 1.5%



## 2.1 Electrical characteristics (curves)

### Figure 2. Safe operating area





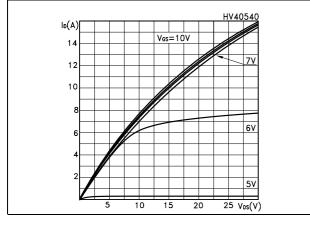
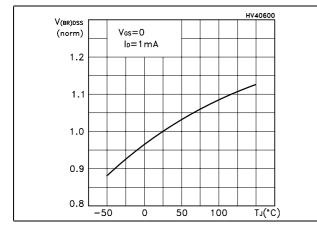
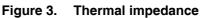
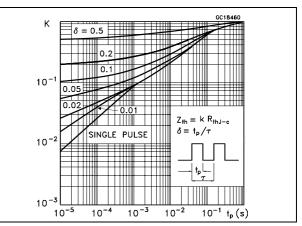


Figure 6. Normalized B<sub>VDSS</sub> vs temperature









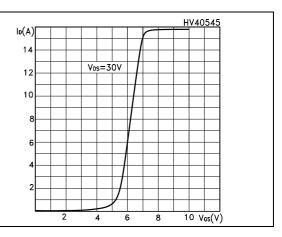
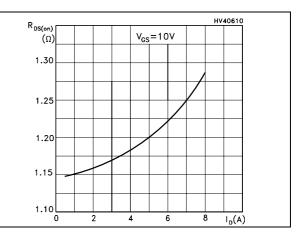
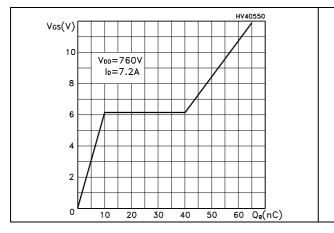
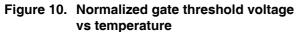


Figure 7. Static drain-source on resistance





### Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations



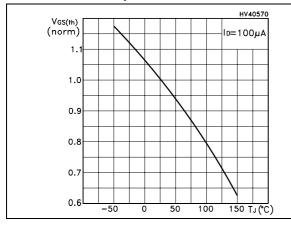


Figure 12. Source-drain diode forward characteristics

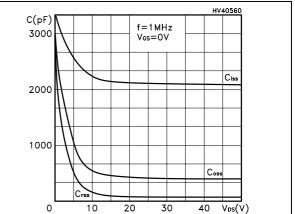


Figure 11. Normalized on resistance vs temperature

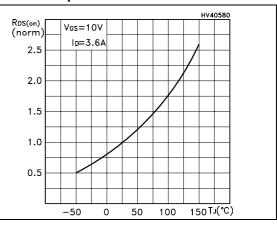
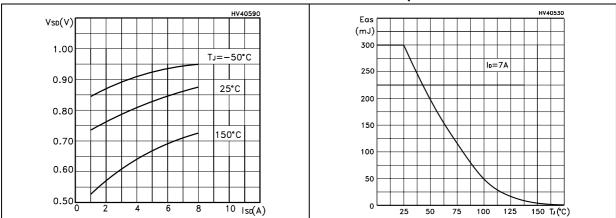


Figure 13. Maximum avalanche energy vs temperature





#### 3 **Test circuits**

Figure 14. Switching times test circuit for resistive load

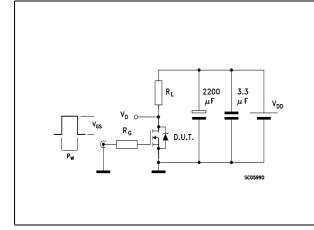
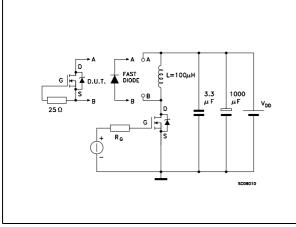


Figure 16. Test circuit for inductive load switching and diode recovery times





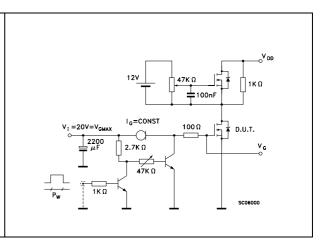


Figure 17. Unclamped Inductive load test circuit

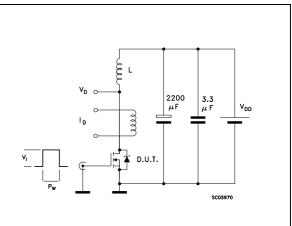
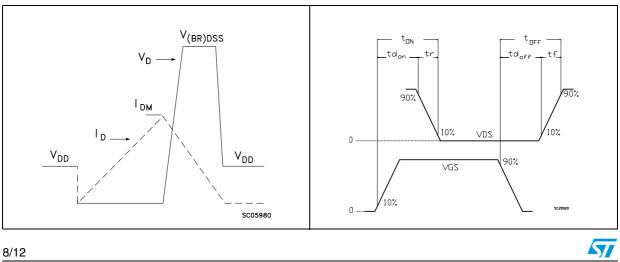


Figure 19. Switching time waveform



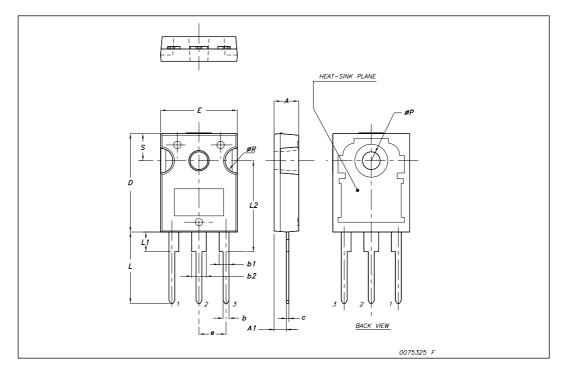
#### Figure 15. Gate charge test circuit

## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



TO-247 Mechanical data				
Dim.	mm.			
	Min.	Тур	Max.	
А	4.85		5.15	
A1	2.20		2.60	
b	1.0		1.40	
b1	2.0		2.40	
b2	3.0		3.40	
С	0.40		0.80	
D	19.85		20.15	
Е	15.45		15.75	
е		5.45		
L	14.20		14.80	
L1	3.70		4.30	
L2		18.50		
øP	3.55		3.65	
øR	4.50		5.50	
S		5.50		





# 5 Revision history

### Table 10. Document revision history

Date	Revision	Changes	
11-Oct-2006	1	Initial release	
03-Jul-2008	2	Updated Figure 6, Figure 7, Figure 9	



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